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What is "[Embedded - Microcontrollers](#)"?

"[Embedded - Microcontrollers](#)" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "[Embedded - Microcontrollers](#)"

Details

Product Status	Active
Core Processor	ARM® Cortex®-M4
Core Size	32-Bit Single-Core
Speed	80MHz
Connectivity	CANbus, I²C, IrDA, LINbus, MMC/SD, QSPI, SAI, SPI, SWPMI, UART/USART, USB OTG
Peripherals	Brown-out Detect/Reset, DMA, LCD, PWM, WDT
Number of I/O	51
Program Memory Size	1MB (1M x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	128K x 8
Voltage - Supply (Vcc/Vdd)	1.71V ~ 3.6V
Data Converters	A/D 16x12b; D/A 2x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	64-LQFP
Supplier Device Package	64-LQFP (10x10)
Purchase URL	https://www.e-xfl.com/product-detail/stmicroelectronics/stm32l486rgt6

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- start-of-conversion triggered by:
 - software trigger
 - internal timers
 - external events
 - start-of-conversion synchronously with first digital filter module (DFSDM1_FLT0)
- analog watchdog feature:
 - low value and high value data threshold registers
 - dedicated configurable Sincx digital filter (order = 1..3, oversampling ratio = 1..32)
 - input from final output data or from selected input digital serial channels
 - continuous monitoring independently from standard conversion
- short circuit detector to detect saturated analog input values (bottom and top range):
 - up to 8-bit counter to detect 1..256 consecutive 0's or 1's on serial data stream
 - monitoring continuously each input serial channel
- break signal generation on analog watchdog event or on short circuit detector event
- extremes detector:
 - storage of minimum and maximum values of final conversion data
 - refreshed by software
- DMA capability to read the final conversion data
- interrupts: end of conversion, overrun, analog watchdog, short circuit, input serial channel clock absence
- “regular” or “injected” conversions:
 - “regular” conversions can be requested at any time or even in continuous mode without having any impact on the timing of “injected” conversions
 - “injected” conversions for precise timing and with high conversion priority

3.23 Random number generator (RNG)

All devices embed an RNG that delivers 32-bit random numbers generated by an integrated analog circuit.

3.24 Advanced encryption standard hardware accelerator (AES)

The devices embed an AES hardware accelerator can be used to both encipher and decipher data using AES algorithm.

The AES peripheral supports:

- Encryption/Decryption using AES Rijndael Block Cipher algorithm
- NIST FIPS 197 compliant implementation of AES encryption/decryption algorithm
- 128-bit and 256-bit register for storing the encryption, decryption or derivation key (4x 32-bit registers)
- Electronic codebook (ECB), Cipher block chaining (CBC), Counter mode (CTR), Galois Counter Mode (GCM), Galois Message Authentication Code mode (GMAC) and Cipher Message Authentication Code mode (CMAC) supported.
- Key scheduler
- Key derivation for decryption
- 128-bit data block processing
- 128-bit, 256-bit key length
- 1x32-bit INPUT buffer and 1x32-bit OUTPUT buffer.
- Register access supporting 32-bit data width only.
- One 128-bit Register for the initialization vector when AES is configured in CBC mode or for the 32-bit counter initialization when CTR mode is selected, GCM mode or CMAC mode.
- Automatic data flow control with support of direct memory access (DMA) using 2 channels, one for incoming data, and one for outgoing data.
- Suspend a message if another message with a higher priority needs to be processed

3.25 Timers and watchdogs

The STM32L486xx includes two advanced control timers, up to nine general-purpose timers, two basic timers, two low-power timers, two watchdog timers and a SysTick timer. The table below compares the features of the advanced control, general purpose and basic timers.

Table 10. Timer feature comparison

Timer type	Timer	Counter resolution	Counter type	Prescaler factor	DMA request generation	Capture/compare channels	Complementary outputs
Advanced control	TIM1, TIM8	16-bit	Up, down, Up/down	Any integer between 1 and 65536	Yes	4	3
General-purpose	TIM2, TIM5	32-bit	Up, down, Up/down	Any integer between 1 and 65536	Yes	4	No
General-purpose	TIM3, TIM4	16-bit	Up, down, Up/down	Any integer between 1 and 65536	Yes	4	No
General-purpose	TIM15	16-bit	Up	Any integer between 1 and 65536	Yes	2	1

3.27 Inter-integrated circuit interface (I2C)

The device embeds 3 I2C. Refer to [Table 11: I2C implementation](#) for the features implementation.

The I²C bus interface handles communications between the microcontroller and the serial I²C bus. It controls all I²C bus-specific sequencing, protocol, arbitration and timing.

The I2C peripheral supports:

- I²C-bus specification and user manual rev. 5 compatibility:
 - Slave and master modes, multimaster capability
 - Standard-mode (Sm), with a bitrate up to 100 kbit/s
 - Fast-mode (Fm), with a bitrate up to 400 kbit/s
 - Fast-mode Plus (Fm+), with a bitrate up to 1 Mbit/s and 20 mA output drive I/Os
 - 7-bit and 10-bit addressing mode, multiple 7-bit slave addresses
 - Programmable setup and hold times
 - Optional clock stretching
- System Management Bus (SMBus) specification rev 2.0 compatibility:
 - Hardware PEC (Packet Error Checking) generation and verification with ACK control
 - Address resolution protocol (ARP) support
 - SMBus alert
- Power System Management Protocol (PMBusTM) specification rev 1.1 compatibility
- Independent clock: a choice of independent clock sources allowing the I2C communication speed to be independent from the PCLK reprogramming. Refer to [Figure 3: Clock tree](#).
- Wakeup from Stop mode on address match
- Programmable analog and digital noise filters
- 1-byte buffer with DMA capability

Table 11. I2C implementation

I2C features ⁽¹⁾	I2C1	I2C2	I2C3
Standard-mode (up to 100 kbit/s)	X	X	X
Fast-mode (up to 400 kbit/s)	X	X	X
Fast-mode Plus with 20mA output drive I/Os (up to 1 Mbit/s)	X	X	X
Programmable analog and digital noise filters	X	X	X
SMBus/PMBus hardware support	X	X	X
Independent clock	X	X	X
Wakeup from Stop 0 / Stop 1 mode on address match	X	X	X
Wakeup from Stop 2 mode on address match	-	-	X

1. X: supported

Table 15. STM32L486xx pin definitions (continued)

Pin Number					Pin name (function after reset)	Pin type	I/O structure	Notes	Pin functions	
LQFP64	WL CSP72	LQFP100	UFBGA132	LQFP144					Alternate functions	Additional functions
29	H3	47	L10	69	PB10	I/O	FT_fl	-	TIM2_CH3, I2C2_SCL, SPI2_SCK, DFSDM1_DATIN7, USART3_TX, LPUART1_RX, QUADSPI_CLK, LCD SEG10, COMP1_OUT, SAI1_SCK_A, EVENTOUT	-
30	G3	48	L11	70	PB11	I/O	FT_fl	-	TIM2_CH4, I2C2_SDA, DFSDM1_CKIN7, USART3_RX, LPUART1_TX, QUADSPI_NCS, LCD SEG11, COMP2_OUT, EVENTOUT	-
31	J2	49	F12	71	VSS	S	-	-	-	-
32	J1	50	G12	72	VDD	S	-	-	-	-
33	H1	51	L12	73	PB12	I/O	FT_I	-	TIM1_BKIN, TIM1_BKIN_COMP2, I2C2_SMBA, SPI2_NSS, DFSDM1_DATIN1, USART3_CK, LPUART1_RTS_DE, TSC_G1_IO1, LCD SEG12, SWPMI1_IO, SAI2_FS_A, TIM15_BKIN, EVENTOUT	-
34	H2	52	K12	74	PB13	I/O	FT_fl	-	TIM1_CH1N, I2C2_SCL, SPI2_SCK, DFSDM1_CKIN1, USART3_CTS, LPUART1_CTS, TSC_G1_IO2, LCD SEG13, SWPMI1_TX, SAI2_SCK_A, TIM15_CH1N, EVENTOUT	-

Table 17. Alternate function AF8 to AF15 (for AF0 to AF7 see [Table 16](#)) (continued)

Port		AF8	AF9	AF10	AF11	AF12	AF13	AF14	AF15
		UART4, UART5, LPUART1	CAN1, TSC	OTG_FS, QUADSPI	LCD	SDMMC1, COMP1, COMP2, FMC, SWPMI1	SAI1, SAI2	TIM2, TIM15, TIM16, TIM17, LPTIM2	EVENTOUT
Port E	PE0	-	-	-	LCD_SEG36	FMC_NBL0	-	TIM16_CH1	EVENTOUT
	PE1	-	-	-	LCD_SEG37	FMC_NBL1	-	TIM17_CH1	EVENTOUT
	PE2	-	TSC_G7_IO1	-	LCD_SEG38	FMC_A23	SAI1_MCLK_A	-	EVENTOUT
	PE3	-	TSC_G7_IO2	-	LCD_SEG39	FMC_A19	SAI1_SD_B	-	EVENTOUT
	PE4	-	TSC_G7_IO3	-	-	FMC_A20	SAI1_FS_A	-	EVENTOUT
	PE5	-	TSC_G7_IO4	-	-	FMC_A21	SAI1_SCK_A	-	EVENTOUT
	PE6	-	-	-	-	FMC_A22	SAI1_SD_A	-	EVENTOUT
	PE7	-	-	-	-	FMC_D4	SAI1_SD_B	-	EVENTOUT
	PE8	-	-	-	-	FMC_D5	SAI1_SCK_B	-	EVENTOUT
	PE9	-	-	-	-	FMC_D6	SAI1_FS_B	-	EVENTOUT
	PE10	-	TSC_G5_IO1	QUADSPI_CLK	-	FMC_D7	SAI1_MCLK_B	-	EVENTOUT
	PE11	-	TSC_G5_IO2	QUADSPI_NCS	-	FMC_D8	-	-	EVENTOUT
	PE12	-	TSC_G5_IO3	QUADSPI_BK1_IO0	-	FMC_D9	-	-	EVENTOUT
	PE13	-	TSC_G5_IO4	QUADSPI_BK1_IO1	-	FMC_D10	-	-	EVENTOUT
	PE14	-	-	QUADSPI_BK1_IO2	-	FMC_D11	-	-	EVENTOUT
	PE15	-	-	QUADSPI_BK1_IO3	-	FMC_D12	-	-	EVENTOUT

Table 18. STM32L486xx memory map and peripheral register boundary addresses⁽¹⁾ (continued)

Bus	Boundary address	Size (bytes)	Peripheral
APB1	0x4000 4800 - 0x4000 4BFF	1 KB	USART3
	0x4000 4400 - 0x4000 47FF	1 KB	USART2
	0x4000 4000 - 0x4000 43FF	1 KB	Reserved
	0x4000 3C00 - 0x4000 3FFF	1 KB	SPI3
	0x4000 3800 - 0x4000 3BFF	1 KB	SPI2
	0x4000 3400 - 0x4000 37FF	1 KB	Reserved
	0x4000 3000 - 0x4000 33FF	1 KB	IWDG
	0x4000 2C00 - 0x4000 2FFF	1 KB	WWDG
	0x4000 2800 - 0x4000 2BFF	1 KB	RTC
	0x4000 2400 - 0x4000 27FF	1 KB	LCD
	0x4000 1800 - 0x4000 23FF	3 KB	Reserved
	0x4000 1400 - 0x4000 17FF	1 KB	TIM7
	0x4000 1000 - 0x4000 13FF	1 KB	TIM6
	0x4000 0C00 - 0x4000 0FFF	1 KB	TIM5

1. The gray color is used for reserved boundary addresses.

Table 30. Typical current consumption in Run and Low-power run modes, with different codes running from Flash, ART disable (continued)

Symbol	Parameter	Conditions			TYP	Unit	TYP	Unit
		-	Voltage scaling	Code	25 °C		25 °C	
I _{DD(LPRun)}	Supply current in Low-power run	$f_{HCLK} = f_{MSI} = 2 \text{ MHz}$ all peripherals disable	Reduced code ⁽¹⁾	358	μA	179	μA/MHz	
			Coremark	392		196		
			Dhrystone 2.1	390		195		
			Fibonacci	385		192		
			While(1)	385		192		

1. Reduced code used for characterization results provided in [Table 26](#), [Table 27](#), [Table 28](#).

Table 31. Typical current consumption in Run and Low-power run modes, with different codes running from SRAM1

Symbol	Parameter	Conditions			TYP	Unit	TYP	Unit
		-	Voltage scaling	Code	25 °C		25 °C	
I _{DD(Run)}	Supply current in Run mode	$f_{HCLK} = f_{HSE}$ up to 48 MHz included, bypass mode PLL ON above 48 MHz all peripherals disable	Range 2 $f_{HCLK} = 26 \text{ MHz}$	Reduced code ⁽¹⁾	2.9	mA	111	μA/MHz
				Coremark	2.9		111	
				Dhrystone 2.1	2.9		111	
				Fibonacci	2.6		100	
				While(1)	2.6		100	
			Range 1 $f_{HCLK} = 80 \text{ MHz}$	Reduced code ⁽¹⁾	10.2	mA	127	μA/MHz
				Coremark	10.4		130	
				Dhrystone 2.1	10.3		129	
				Fibonacci	9.6		120	
				While(1)	9.3		116	
I _{DD(LPRun)}	Supply current in Low-power run	$f_{HCLK} = f_{MSI} = 2 \text{ MHz}$ all peripherals disable	Reduced code ⁽¹⁾	242	μA	121	μA/MHz	
			Coremark	242		121		
			Dhrystone 2.1	242		121		
			Fibonacci	225		112		
			While(1)	242		121		

1. Reduced code used for characterization results provided in [Table 26](#), [Table 27](#), [Table 28](#).

Table 35. Current consumption in Stop 1 mode

Symbol	Parameter	Conditions			TYP					MAX ⁽¹⁾					Unit
		-	-	V _{DD}	25 °C	55 °C	85 °C	105 °C	125 °C	25 °C	55 °C	85 °C	105 °C	125 °C	
I _{DD} (Stop 1)	Supply current in Stop 1 mode, RTC disabled	-	LCD disabled	1.8 V	6.59	24.7	92.7	208	437	16	62	232	520	1093	µA
				2.4 V	6.65	24.8	92.9	209	439	17	62	232	523	1098	
				3 V	6.65	24.9	93.3	210	442	17	62	233	525	1105	
				3.6 V	6.70	25.1	93.8	212	447	17	63	235	530	1118	
		-	LCD enabled ⁽²⁾ clocked by LSI	1.8 V	7.00	25.2	97.2	219	461	18	63	243	548	1153	
				2.4 V	7.14	25.4	97.5	220	463	18	64	244	550	1158	
				3 V	7.24	25.7	97.7	221	465	18	64	244	553	1163	
				3.6 V	7.36	26.1	98.7	223	471	18	65	247	558	1178	
I _{DD} (Stop 1 with RTC)	Supply current in stop 1 mode, RTC enabled	RTC clocked by LSI	LCD disabled	1.8 V	6.88	25.0	93.1	209	439	17	63	233	523	1098	µA
				2.4 V	7.02	25.2	93.7	210	441	18	63	234	525	1103	
				3 V	7.12	25.4	94.2	212	444	18	64	236	530	1110	
				3.6 V	7.25	25.7	95.2	214	449	18	64	238	535	1123	
		LCD enabled ⁽²⁾	LCD enabled ⁽²⁾	1.8 V	7.01	26.1	99.0	223	467	18	65	248	558	1168	
				2.4 V	7.14	26.3	99.6	225	470	18	66	249	563	1175	
				3 V	7.31	26.6	100.0	226	474	18	67	250	565	1185	
				3.6 V	7.41	26.9	102.0	229	480	19	67	255	573	1200	
		RTC clocked by LSE bypassed at 32768 Hz	LCD disabled	1.8 V	6.91	25.2	93.4	210	440	17	63	234	525	1100	
				2.4 V	7.04	25.3	94.2	211	443	18	63	236	528	1108	
				3 V	7.19	25.7	95.0	212	446	18	64	238	530	1115	
				3.6 V	7.97	26.0	96.1	215	451	20	65	240	538	1128	
		RTC clocked by LSE quartz ⁽³⁾ in low drive mode	LCD disabled	1.8 V	6.85	25.0	93.0	208.3	-	17	63	233	521	-	
				2.4 V	6.94	25.1	93.2	209.3	-	17	63	233	523	-	
				3 V	7.10	25.2	93.6	210.3	-	18	63	234	526	-	
				3.6 V	7.34	25.4	94.1	212.3	-	18	64	235	531	-	



On-chip peripheral current consumption

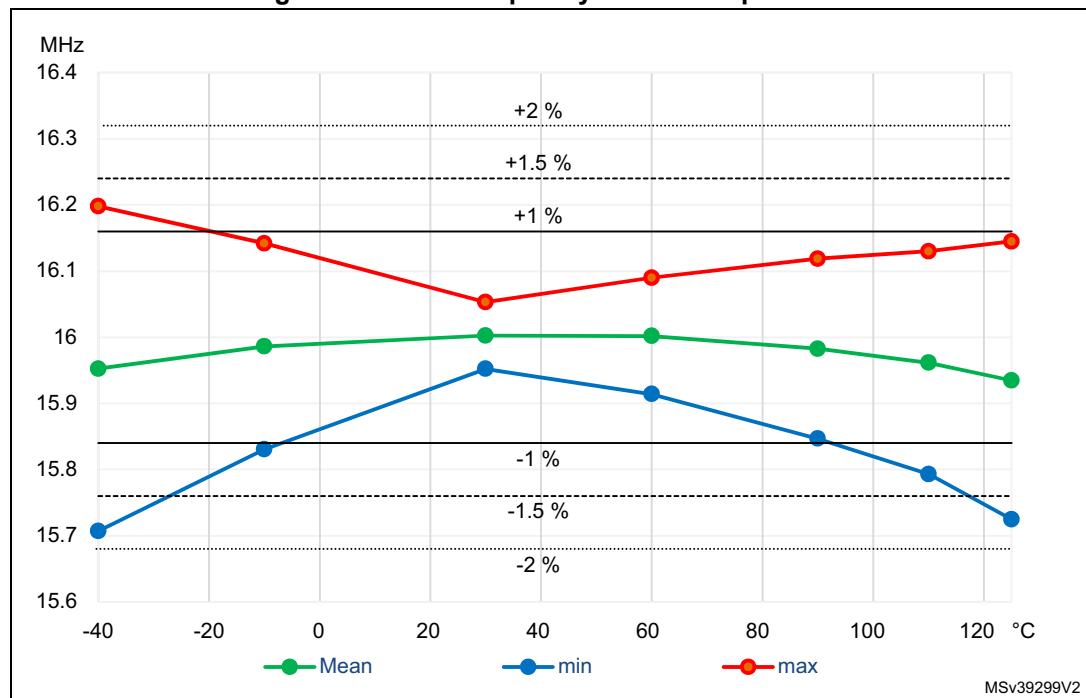
The current consumption of the on-chip peripherals is given in [Table 40](#). The MCU is placed under the following conditions:

- All I/O pins are in Analog mode
- The given value is calculated by measuring the difference of the current consumptions:
 - when the peripheral is clocked on
 - when the peripheral is clocked off
- Ambient operating temperature and supply voltage conditions summarized in [Table 19: Voltage characteristics](#)
- The power consumption of the digital part of the on-chip peripherals is given in [Table 40](#). The power consumption of the analog part of the peripherals (where applicable) is indicated in each related section of the datasheet.

Table 40. Peripheral current consumption

Peripheral	Range 1	Range 2	Low-power run and sleep	Unit
AHB	Bus Matrix ⁽¹⁾	4.5	3.7	4.1
	ADC independent clock domain	0.4	0.1	0.2
	ADC AHB clock domain	5.5	4.7	5.5
	AES	1.7	1.5	1.6
	CRC	0.4	0.2	0.3
	DMA1	1.4	1.3	1.4
	DMA2	1.5	1.3	1.4
	FLASH	6.2	5.2	5.8
	FMC	8.9	7.5	8.4
	GPIOA ⁽²⁾	4.8	3.8	4.4
	GPIOB ⁽²⁾	4.8	4.0	4.6
	GPIOC ⁽²⁾	4.5	3.8	4.3
	GPIOD ⁽²⁾	4.6	3.9	4.4
	GPIOE ⁽²⁾	5.2	4.5	4.9
	GPIOF ⁽²⁾	5.9	4.9	5.7
	GPIOG ⁽²⁾	4.3	3.8	4.2
	GPIOH ⁽²⁾	0.7	0.6	0.8
	OTG_FS independent clock domain	23.2	NA	NA
	OTG_FS AHB clock domain	16.4	NA	NA
	QUADSPI	7.8	6.7	7.3
	RNG independent clock domain	2.2	NA	NA
	RNG AHB clock domain	0.6	NA	NA
	SRAM1	0.9	0.8	0.9

µA/MHz

Figure 20. HSI16 frequency versus temperature

6.3.14 I/O port characteristics

General input/output characteristics

Unless otherwise specified, the parameters given in [Table 59](#) are derived from tests performed under the conditions summarized in [Table 22: General operating conditions](#). All I/Os are designed as CMOS- and TTL-compliant (except BOOT0).

Table 59. I/O static characteristics

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
$V_{IL}^{(1)}$	I/O input low level voltage except BOOT0	$1.62 \text{ V} < V_{DDIOx} < 3.6 \text{ V}$	-	-	$0.3 \times V_{DDIOx}^{(2)}$	V
	I/O input low level voltage except BOOT0	$1.62 \text{ V} < V_{DDIOx} < 3.6 \text{ V}$	-	-	$0.39 \times V_{DDIOx} - 0.06^{(3)}$	
	I/O input low level voltage except BOOT0	$1.08 \text{ V} < V_{DDIOx} < 1.62 \text{ V}$	-	-	$0.43 \times V_{DDIOx} - 0.1^{(3)}$	
	BOOT0 I/O input low level voltage	$1.62 \text{ V} < V_{DDIOx} < 3.6 \text{ V}$	-	-	$0.17 \times V_{DDIOx}^{(3)}$	
$V_{IH}^{(1)}$	I/O input high level voltage except BOOT0	$1.62 \text{ V} < V_{DDIOx} < 3.6 \text{ V}$	$0.7 \times V_{DDIOx}^{(2)}$	-	-	V
	I/O input high level voltage except BOOT0	$1.62 \text{ V} < V_{DDIOx} < 3.6 \text{ V}$	$0.49 \times V_{DDIOx} + 0.26^{(3)}$	-	-	
	I/O input high level voltage except BOOT0	$1.08 \text{ V} < V_{DDIOx} < 1.62 \text{ V}$	$0.61 \times V_{DDIOx} + 0.05^{(3)}$	-	-	
	BOOT0 I/O input high level voltage	$1.62 \text{ V} < V_{DDIOx} < 3.6 \text{ V}$	$0.77 \times V_{DDIOx}^{(3)}$	-	-	
$V_{hys}^{(3)}$	TT_xx, FT_xxx and NRST I/O input hysteresis	$1.62 \text{ V} < V_{DDIOx} < 3.6 \text{ V}$	-	200	-	mV
	FT_sx	$1.08 \text{ V} < V_{DDIOx} < 1.62 \text{ V}$	-	150	-	
	BOOT0 I/O input hysteresis	$1.62 \text{ V} < V_{DDIOx} < 3.6 \text{ V}$	-	200	-	

Table 67. ADC accuracy - limited test conditions 2⁽¹⁾⁽²⁾⁽³⁾ (continued)

Symbol	Parameter	Conditions ⁽⁴⁾			Min	Typ	Max	Unit
THD	Total harmonic distortion	ADC clock frequency ≤ 80 MHz, Sampling rate ≤ 5.33 Msps, $2 \text{ V} \leq V_{DDA}$	Single ended	Fast channel (max speed)	-	-74	-65	dB
				Slow channel (max speed)	-	-74	-67	
			Differential	Fast channel (max speed)	-	-79	-70	
				Slow channel (max speed)	-	-79	-71	

1. Guaranteed by design.
2. ADC DC accuracy values are measured after internal calibration.
3. ADC accuracy vs. negative Injection Current: Injecting negative current on any analog input pins should be avoided as this significantly reduces the accuracy of the conversion being performed on another analog input. It is recommended to add a Schottky diode (pin to ground) to analog pins which may potentially inject negative current.
4. The I/O analog switch voltage booster is enable when $V_{DDA} < 2.4 \text{ V}$ (BOOSTEN = 1 in the SYSCFG_CFGR1 when $V_{DDA} < 2.4 \text{ V}$). It is disable when $V_{DDA} \geq 2.4 \text{ V}$. No oversampling.

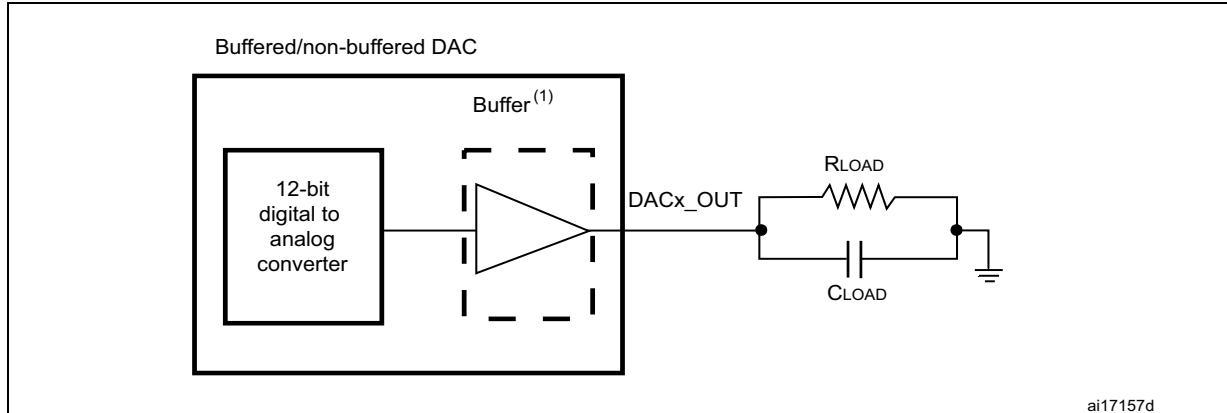
Table 68. ADC accuracy - limited test conditions 3⁽¹⁾⁽²⁾⁽³⁾ (continued)

Symbol	Parameter	Conditions ⁽⁴⁾			Min	Typ	Max	Unit
THD	Total harmonic distortion	ADC clock frequency ≤ 80 MHz, Sampling rate ≤ 5.33 Msps, $1.65 \text{ V} \leq V_{DDA} = V_{REF+} \leq 3.6 \text{ V}$, Voltage scaling Range 1	Single ended	Fast channel (max speed)	-	-69	-67	dB
				Slow channel (max speed)	-	-71	-67	
			Differential	Fast channel (max speed)	-	-72	-71	
				Slow channel (max speed)	-	-72	-71	

1. Guaranteed by design.
2. ADC DC accuracy values are measured after internal calibration.
3. ADC accuracy vs. negative Injection Current: Injecting negative current on any analog input pins should be avoided as this significantly reduces the accuracy of the conversion being performed on another analog input. It is recommended to add a Schottky diode (pin to ground) to analog pins which may potentially inject negative current.
4. The I/O analog switch voltage booster is enable when $V_{DDA} < 2.4 \text{ V}$ (BOOSTEN = 1 in the SYSCFG_CFGR1 when $V_{DDA} < 2.4 \text{ V}$). It is disable when $V_{DDA} \geq 2.4 \text{ V}$. No oversampling.

4. T_{on} is the Refresh phase duration. T_{off} is the Hold phase duration. Refer to RM0351 reference manual for more details.

Figure 27. 12-bit buffered / non-buffered DAC



1. The DAC integrates an output buffer that can be used to reduce the output impedance and to drive external loads directly without the use of an external operational amplifier. The buffer can be bypassed by configuring the BOFFx bit in the DAC_CR register.

Table 71. DAC accuracy⁽¹⁾

Symbol	Parameter	Conditions		Min	Typ	Max	Unit
DNL	Differential non linearity ⁽²⁾	DAC output buffer ON		-	-	± 2	LSB
		DAC output buffer OFF		-	-	± 2	
-	monotonicity	10 bits			guaranteed		
INL	Integral non linearity ⁽³⁾	DAC output buffer ON CL \leq 50 pF, RL \geq 5 k Ω		-	-	± 4	LSB
		DAC output buffer OFF CL \leq 50 pF, no RL		-	-	± 4	
Offset	Offset error at code 0x800 ⁽³⁾	DAC output buffer ON CL \leq 50 pF, RL \geq 5 k Ω	$V_{REF+} = 3.6$ V	-	-	± 12	LSB
			$V_{REF+} = 1.8$ V	-	-	± 25	
		DAC output buffer OFF CL \leq 50 pF, no RL		-	-	± 8	
Offset1	Offset error at code 0x001 ⁽⁴⁾	DAC output buffer OFF CL \leq 50 pF, no RL		-	-	± 5	%
OffsetCal	Offset Error at code 0x800 after calibration	DAC output buffer ON CL \leq 50 pF, RL \geq 5 k Ω	$V_{REF+} = 3.6$ V	-	-	± 5	
			$V_{REF+} = 1.8$ V	-	-	± 7	
Gain	Gain error ⁽⁵⁾	DAC output buffer ON CL \leq 50 pF, RL \geq 5 k Ω		-	-	± 0.5	%
		DAC output buffer OFF CL \leq 50 pF, no RL		-	-	± 0.5	

Table 102. Synchronous non-multiplexed PSRAM write timings⁽¹⁾⁽²⁾

Symbol	Parameter	Min	Max	Unit
$t_w(CLK)$	FMC_CLK period	$2T_{HCLK}-0.5$	-	ns
$t_d(CLKL-NExL)$	FMC_CLK low to FMC_NEx low ($x=0..2$)	-	2	
$t_d(CLKH-NExH)$	FMC_CLK high to FMC_NEx high ($x=0..2$)	$T_{HCLK}+0.5$	-	
$t_d(CLKL-NADVL)$	FMC_CLK low to FMC_NADV low	-	2	
$t_d(CLKL-NADVH)$	FMC_CLK low to FMC_NADV high	2.5	-	
$t_d(CLKL-AV)$	FMC_CLK low to FMC_Ax valid ($x=16..25$)	-	5	
$t_d(CLKH-AIV)$	FMC_CLK high to FMC_Ax invalid ($x=16..25$)	$T_{HCLK}-1$	-	
$t_d(CLKL-NWEL)$	FMC_CLK low to FMC_NWE low	-	2	
$t_d(CLKH-NWEH)$	FMC_CLK high to FMC_NWE high	$T_{HCLK}-1$	-	
$t_d(CLKL-Data)$	FMC_D[15:0] valid data after FMC_CLK low	-	4.5	
$t_d(CLKL-NBLL)$	FMC_CLK low to FMC_NBL low	1.5	-	
$t_d(CLKH-NBLH)$	FMC_CLK high to FMC_NBL high	$T_{HCLK}+1$	-	
$t_{su}(NWAIT-CLKH)$	FMC_NWAIT valid before FMC_CLK high	0	-	
$t_h(CLKH-NWAIT)$	FMC_NWAIT valid after FMC_CLK high	4	-	

1. CL = 30 pF.

2. Guaranteed by characterization results.

NAND controller waveforms and timings

Figure 45 through *Figure 48* represent synchronous waveforms, and *Table 103* and *Table 104* provide the corresponding timings. The results shown in these tables are obtained with the following FMC configuration:

- COM.FMC_SetupTime = 0x02
- COM.FMC_WaitSetupTime = 0x03
- COM.FMC_HoldSetupTime = 0x02
- COM.FMC_HiZSetupTime = 0x03
- ATT.FMC_SetupTime = 0x01
- ATT.FMC_WaitSetupTime = 0x03
- ATT.FMC_HoldSetupTime = 0x02
- ATT.FMC_HiZSetupTime = 0x03
- Bank = FMC_Bank_NAND
- MemoryDataWidth = FMC_MemoryDataWidth_16b
- ECC = FMC_ECC_Enable
- ECCPageSize = FMC_ECCPageSize_512Bytes
- TCLRSetupTime = 0
- TARSetupTime = 0

In all timing tables, the T_{HCLK} is the HCLK clock period.

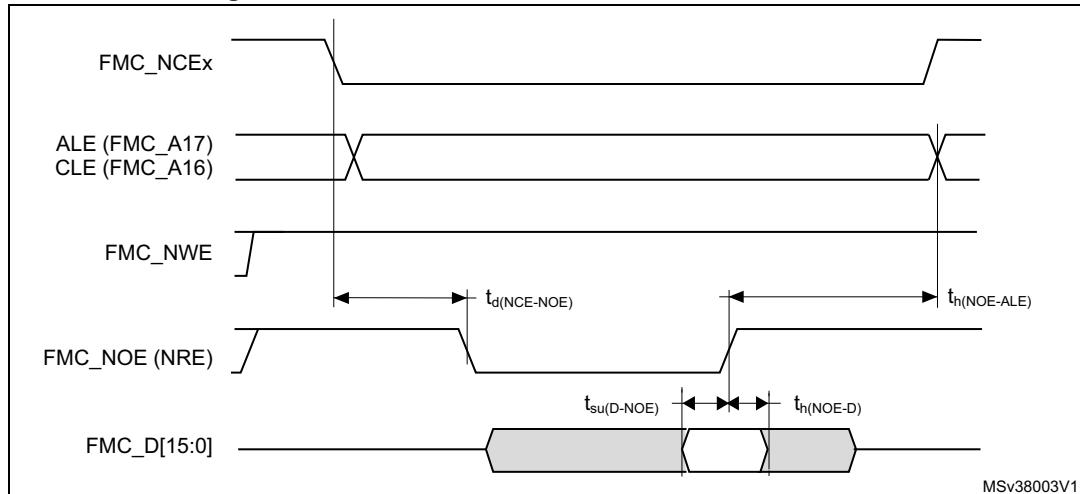
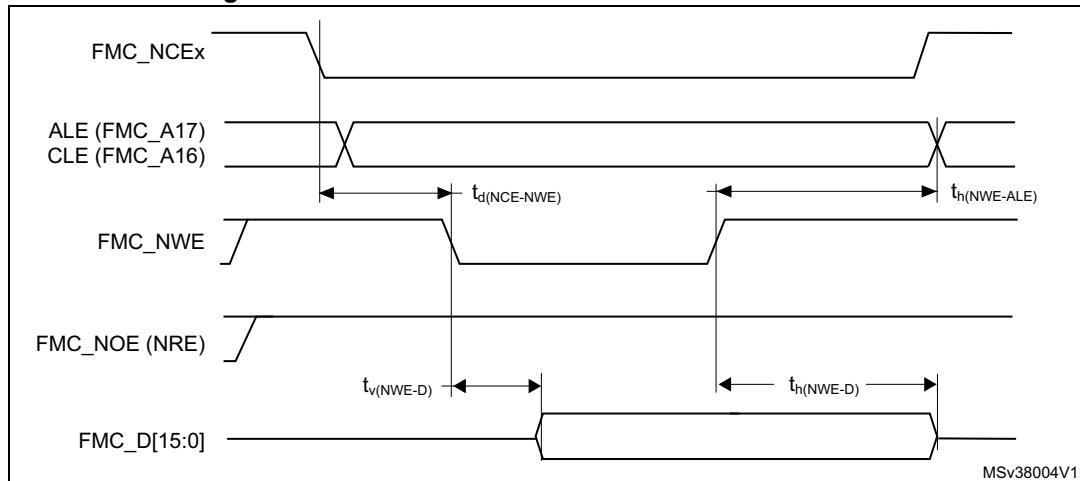
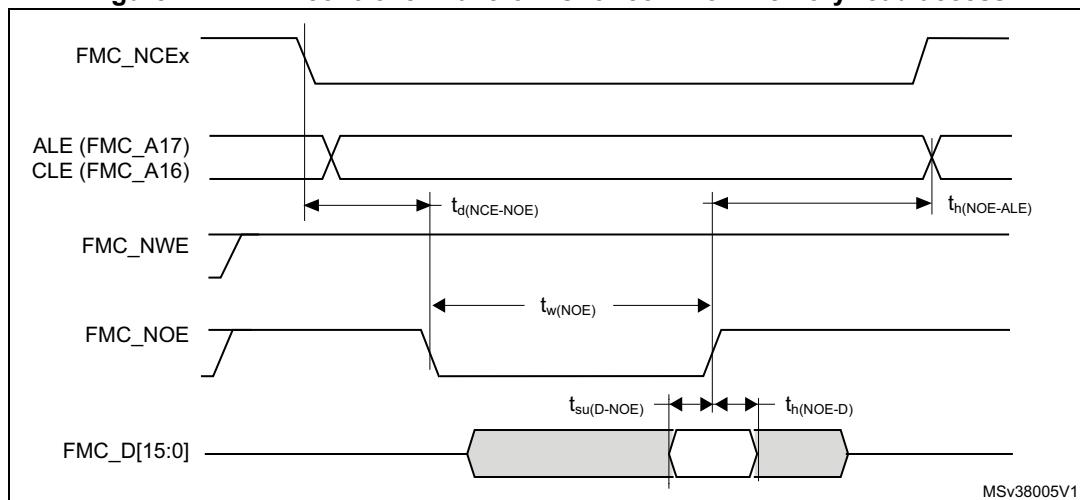
Figure 45. NAND controller waveforms for read access**Figure 46. NAND controller waveforms for write access****Figure 47. NAND controller waveforms for common memory read access**

Table 110. WLCSP72 - 72-ball, 4.4084 x 3.7594 mm, 0.4 mm pitch wafer level chip scale package mechanical data (continued)

Symbol	millimeters			inches⁽¹⁾		
	Min	Typ	Max	Min	Typ	Max
G	-	0.2797	-	-	0.0110	-
aaa	-	0.100	-	-	0.0039	-
bbb	-	0.100	-	-	0.0039	-
ccc	-	0.100	-	-	0.0039	-
ddd	-	0.050	-	-	0.0020	-
eee	-	0.050	-	-	0.0020	-

1. Values in inches are converted from mm and rounded to 4 decimal digits.

2. Back side coating

3. Dimension is measured at the maximum bump diameter parallel to primary datum Z.

Figure 59. WLCSP72 - 72-ball, 4.4084 x 3.7594 mm, 0.4 mm pitch wafer level chip scale package recommended footprint

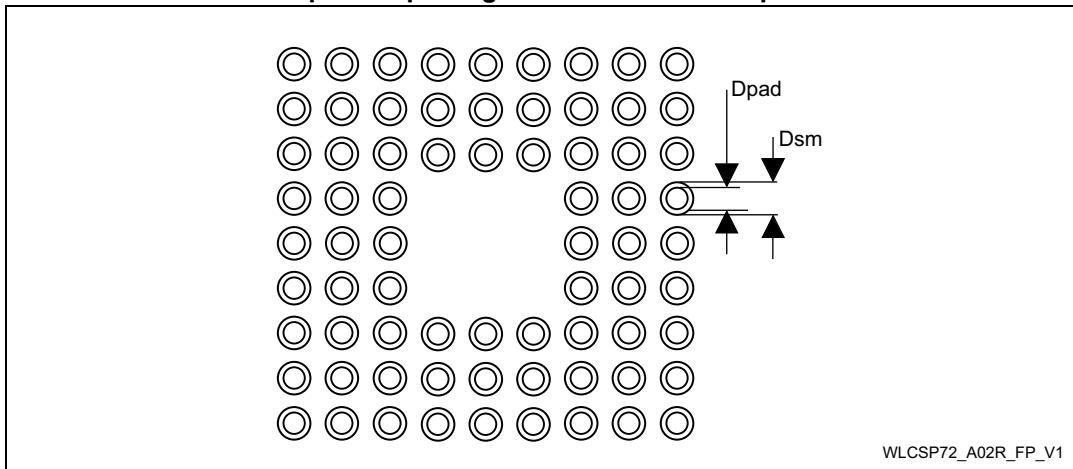


Table 111. WLCSP72 recommended PCB design rules (0.4 mm pitch BGA)

Dimension	Recommended values
Pitch	0.4 mm
Dpad	0.225 mm
Dsm	0.290 mm typ. (depends on the solder mask registration tolerance)
Stencil opening	0.250 mm
Stencil thickness	0.100 mm

Using the values obtained in [Table 113](#) $T_{J\max}$ is calculated as follows:

- For LQFP64, 45 °C/W

$$T_{J\max} = 100 \text{ }^{\circ}\text{C} + (45 \text{ }^{\circ}\text{C/W} \times 134 \text{ mW}) = 100 \text{ }^{\circ}\text{C} + 6.03 \text{ }^{\circ}\text{C} = 106.03 \text{ }^{\circ}\text{C}$$

This is above the range of the suffix 6 version parts ($-40 < T_J < 105 \text{ }^{\circ}\text{C}$).

In this case, parts must be ordered at least with the temperature range suffix 7 (see [Section 8: Part numbering](#)) unless we reduce the power dissipation in order to be able to use suffix 6 parts.

Refer to [Figure 64](#) to select the required temperature range (suffix 6 or 7) according to your ambient temperature or power requirements.

Figure 64. LQFP64 P_D max vs. T_A

